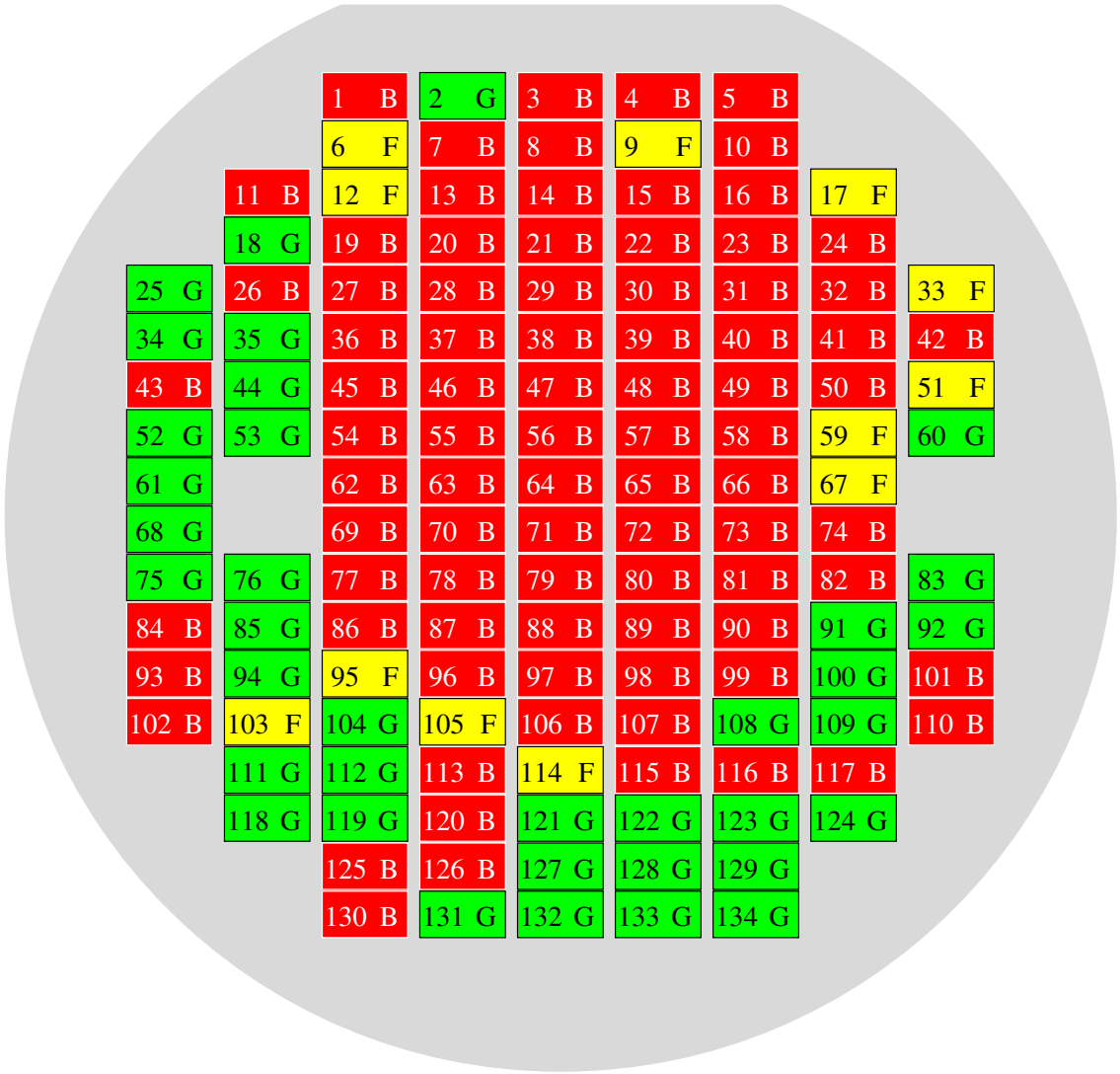
Die quality map for wafer 167 s/n: Y21316-12-01

Date: 07/02/99



# B	Bad die
# F	Fair die
# G	Good die
# N	No info
# *	Manually tagged